

**Search Notes**

Application/Control No.

10/657,350

Examiner

Sin J. Lee

Applicant(s)/Patent under  
Reexamination

BOYKIN ET AL.

Art Unit

1752

**SEARCHED**

Class	Subclass	Date	Examiner
430	270.1	5-1-05	SJL
↓	273.1	↓	↓

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR